

<b>Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10750568	NGUYEN ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
307	64	06/22/2006	HK
307	150	06/21/2006	HK

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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Notes	Date	Examiner
307/64-66; 320/\$ (no search) (consulted Adolf Berhane)	06/22/2006	HK
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	06/21/2006	HK
EAST (US-PGPUB,USPAT) - See Search History Printout	06/22/2006	HK
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